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STC HIGHLIGHTS SIGNIFICANT GLOBAL PROGRESS AT SEMICON JAPAN 2006

NIWOT, Colorado, December 4, 2006 — The Semiconductor Test Consortium, Inc. (STC), the leading proponent of worldwide adoption of automatic test equipment (ATE) Open Architecture, today announced it will highlight the Open Interfaces Initiative to enable development of ATE peripheral interface standards during SEMICON Japan 2006, December 6-8, at Makuhari Messe, Chiba, Japan. This initiative treats the ATE as a “black box,” enabling greater portability of test collateral through higher-level abstraction of user programming, equipment integration and device interconnect. STC will also feature OPENSTAR-compliant modules from member companies Apria Technology and Advantest Corp., underscoring the consortium’s proven ability to create and implement a common test architecture that is completely open, documented and supported via solutions available from ATE vendors as well as third-party developers.

Global STC membership has grown significantly this year, led by 11 new corporate members. Corporate membership now totals 44, including six of the world’s top 11 semiconductor companies. In particular, European membership has shown an upsurge, with the recent additions to the STC roster of Interface Technologies Europe Ltd., Microhandling GmbH, Rasco GmbH and Rood Technology GmbH & Co.

“2006 has been a phenomenal year for the consortium,” stated STC Manager and Bob Helsel. “We launched the Open Interfaces Initiative, which will include eight new technical working groups and the OPENSTAR Ecosystem has gained substantial traction. The remarkable attendance at our first Global STC Conference in March, combined with the outstanding level of expertise represented by our elected STC board, provides further indication of the significant momentum and interest in the consortium.”

In conjunction with SEMICON Japan, the STC will hold a general meeting on December 7, to be followed by the annual SEMICON Japan dinner meeting. Both events will be held at the APA Hotel in Makuhari.

STC Exhibits at SEMICON Japan 2006 – Booth #10B-604

Apria Technology will be showing its OPENSTAR-compliant OC800 arbitrary waveform generator (AWG) module, which cost-effectively meets the diverse and stringent mixed-signal test requirements for baseband products such as Gigabit Ethernet, DVD, digital TV and I-Q applications.

Advantest will display its high performance OPENSTAR-compliant 8-channel Jitter Module, which delivers highly integrated functionality on a single board, helping semiconductor manufacturers realize greater utilization of their testers, ease of use and reduced overall costs.

About the Semiconductor Test Consortium

The Semiconductor Test Consortium was founded in 2003 to develop a common test architecture that is completely open, documented and supported via solutions available from all ATE vendors. Open to all companies throughout the semiconductor supply chain with a vested interest in the test sector, the consortium is focused on the following goals: formalizing a broadened STC scope with new working groups and specification structure; fostering pre-competitive collaboration among industry participants toward development of value-added standards; emphasizing new initiatives, the value of work being accomplished and the contributions to the industry; and continuing STC efforts to fully enable the OPENSTAR Ecosystem. Today, there are a total of 93 members, which includes 43 semiconductor, equipment and instrumentation companies worldwide and 38 universities in Europe, Japan, China and the United States, in addition to eight STIL users and four individuals support the STC. More information can be found at www.semitest.org

OPENSTAR is a registered trademark of the Semiconductor Test Consortium.